

**Search Notes**

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Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

OOYA ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	285	6/29/2007	HN
330	295	6/29/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/29/2007	HN